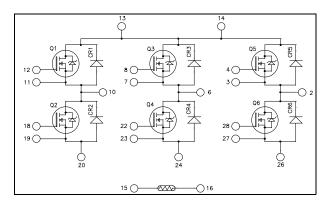
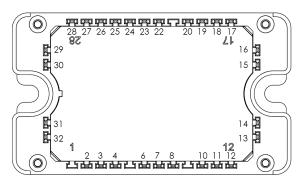


## 3 phase bridge SiC MOSFET Power Module





Pins 20, 24 & 26 must be shorted together to perform a 3 phase bridge.

## 

### Application

- Welding converters
- Switched Mode Power Supplies
- Uninterruptible Power Supplies
- Motor control

#### **Features**

#### • SiC Power MOSFET

- High speed switching
- Low R<sub>DS(on)</sub>
- Ultra low loss

#### • SiC Schottky Diode

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Very low stray inductance
- Kelvin source for easy drive
- Internal thermistor for temperature monitoring
- AlN substrate for improved thermal performance

#### **Benefits**

- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- RoHS Compliant

### All ratings @ $T_i = 25^{\circ}C$ unless otherwise specified

#### Absolute maximum ratings (per SiC MOSFET)

Symbol	Parameter		Max ratings	Unit
$V_{ m DSS}$	Drain - Source Voltage		1200	V
ī	Continuous Drain Current	$T_c = 25$ °C	74	
$I_{\mathrm{D}}$	Continuous Diam Current	$T_c = 80$ °C	58	Α
$I_{DM}$	Pulsed Drain current		150	
$V_{GS}$	Gate - Source Voltage		-10/25V	V
$R_{DSon}$	Drain - Source ON Resistance		34	mΩ
$P_{D}$	Power Dissipation	$T_c = 25^{\circ}C$	375	W

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

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### Power Matters.™

## **Electrical Characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions			Тур	Max	Unit
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ , $V_{DS} = 1200V$			10	100	μΑ
R <sub>DS(on)</sub>	Drain – Source on Resistance	$V_{GS} = 20V$	$T_j = 25^{\circ}C$		25	34	
		$I_D = 50A$	$T_j = 175$ °C		52		mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 15 \text{mA}$		2	2.6	4	V
$I_{GSS}$	Gate – Source Leakage Current	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				600	nA

## **Dynamic Characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$			2788		
$C_{oss}$	Output Capacitance	$V_{\rm DS} = 1000V$			220		pF
$C_{rss}$	Reverse Transfer Capacitance	f = 1MHz			15		
$Q_{g}$	Total gate Charge	$V_{GS} = -5/+20V$			161		
$Q_{gs}$	Gate – Source Charge	$V_{Bus} = 800V$			46		nC
$Q_{gd}$	Gate – Drain Charge	$I_D = 50A$			50		
$T_{d(on)}$	Turn-on Delay Time	$\begin{array}{c} - V_{GS} = -5/+20V \\ V_{Bus} = 800V \\ I_{D} = 50A \end{array}$			21		
$T_{\rm r}$	Rise Time				19		ns
$T_{d(off)}$	Turn-off Delay Time				50		
$T_{\mathrm{f}}$	Fall Time	$R_{\rm L} = 16\Omega \; ; \; R_{\rm Gext} = 20$	)(2		30		
Eon	Turn on Energy	Inductive Switching $V_{GS} = -5/+20V$ $V_{Bus} = 600V$	$T_j = 150^{\circ}C$		1.1		mJ
$E_{\text{off}}$	Turn off Energy	$I_{D} = 50A$ $R_{Gext} = 20\Omega$	$T_j = 150^{\circ}C$		0.6		Ш
$R_{Gint}$	Internal gate resistance				1.1		Ω
$R_{\text{thJC}}$	Junction to Case Thermal Resistance	e				0.4	°C/W

### **Body diode ratings and characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
$V_{SD}$	Diode Forward Voltage	$V_{GS} = -5V$	$T_j = 25^{\circ}C$		4		V
		$I_{SD} = 25A$	$T_j = 175$ °C		3.5		v
t <sub>rr</sub>	Reverse Recovery Time	$\begin{split} I_{SD} &= 50 A \; ; \; V_{GS} = \text{-}5V \\ V_{R} &= 800 V \; ; \; di_{F}/dt = 1000 A/\mu s \end{split}$			45		ns
Q <sub>rr</sub>	Reverse Recovery Charge				406		nC
$I_{rr}$	Reverse Recovery Current				13.5		Α

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# SiC schottky diode ratings and characteristics (per SiC diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit		
$V_{RRM}$	Peak Repetitive Reverse Voltage					1200	V		
Ţ	Reverse Leakage Current	$V_{p}=1200V$	$T_j = 25^{\circ}C$		35	200	μA		
$I_{RRM}$	Reverse Leakage Current		V <sub>R</sub> -1200 V	V <sub>R</sub> -1200 V	V <sub>R</sub> -1200 V	$T_j = 175$ °C		65	400
$I_{\mathrm{F}}$	DC Forward Current		Tc = 100°C		20		A		
$V_{\mathrm{F}}$	$V_{\rm F}$ Diode Forward Voltage $I_{\rm F} = 20 {\rm A}$	$T_i = 25^{\circ}C$		1.5	1.8	V			
V F	From T <sub>i</sub> = $175^{\circ}$ C		$T_i = 175^{\circ}C$		2.2	3	v		
Qc	Total Capacitive Charge	$I_F = 20A, V_R = 1200V$ di/dt = $500A/\mu s$			99		nC		
С	Total Capacitance	$f = 1MHz, V_R = 400V$			93		рF		
		$f = 1 MHz, V_R$	= 800V		67		pr		
$R_{thJC}$	Junction to Case Thermal Resistance					1.1	°C/W		

### Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

Symbol	Characteristic		Min	Тур	Max	Unit
R <sub>25</sub>	Resistance @ 25°C			50		kΩ
$\Delta R_{25}/R_{25}$				5		%
B <sub>25/85</sub>	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta B/B$		T <sub>C</sub> =100°C		4		%

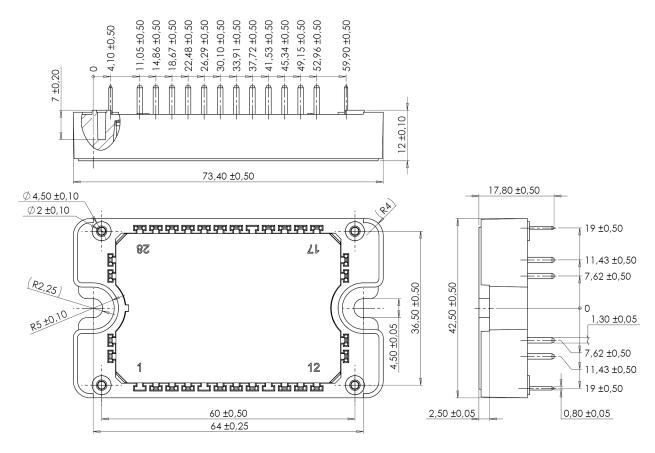
$$R_T = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$
 T: Thermistor temperature R<sub>T</sub>: Thermistor value at T

## Thermal and package characteristics

Symbol	Characteristic			Min	Max	Unit
$V_{ISOL}$	RMS Isolation Voltage, any terminal to case t	4000		V		
$T_{J}$	Operating junction temperature range				175	
$T_{JOP}$	Recommended junction temperature under switching conditions			-40	T <sub>J</sub> max -25	°C
$T_{STG}$	Storage Temperature Range			-40	125	C
$T_{\rm C}$	Operating Case Temperature			-40	125	
Torque	Mounting torque	To heatsink	M4	2	3	N.m
Wt	Package Weight				110	g



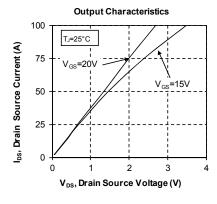
### Package outline (dimensions in mm)

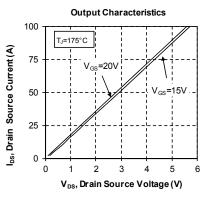


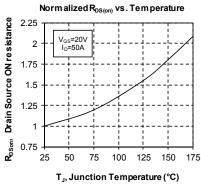
See application note 1906 - Mounting Instructions for SP3F Power Modules on www.microsemi.com

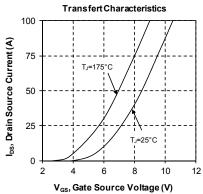


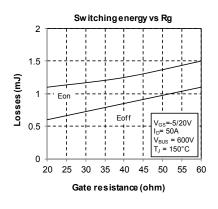
### **Typical SiC MOSFET Performance Curve**

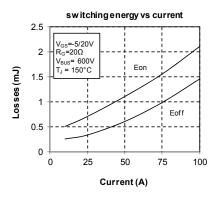


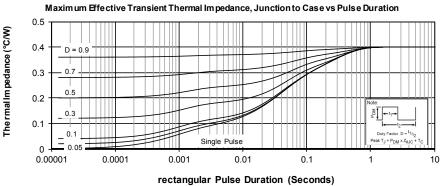






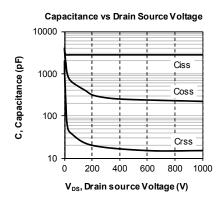




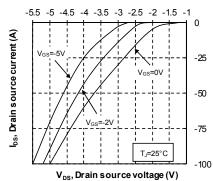




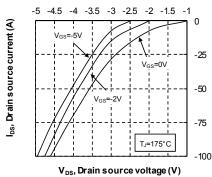
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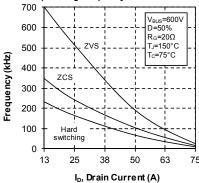
#### **Body diode Characteristics**



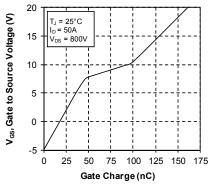
**Body diode Characteristics** 



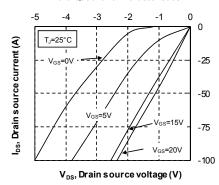
Operating Frequency vs Drain Current



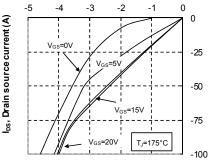
Gate Charge vs Gate Source Voltage



3rd Quadrant Characteristics



3rd Quadrant Characteristics

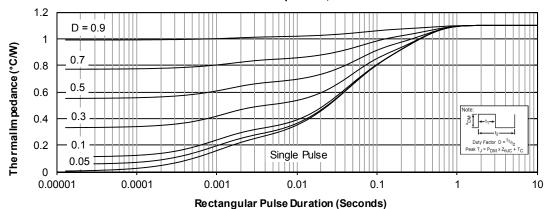


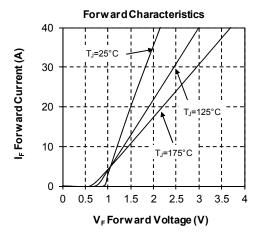
 $V_{DS}$ , Drain source voltage (V)

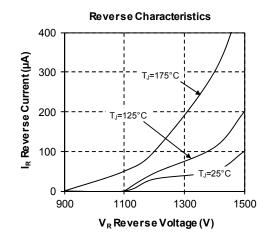


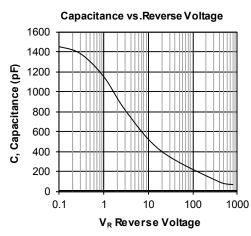
### Typical SiC diode Performance Curve

#### Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration









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